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Keywords: atom, model, theory, project, nanosystems, structure, inter-atomic and inter-molecular interaction, nanotechnology.
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Keywords: resistor, thin film contact, resistance, current density, power dissipation, potential difference, distribution, non-uniformity, nano-effect.
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Keywords: microphotonics, opal matrixes, ferrite nanoparticles, microwave measurements.
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Keywords: silicon on sapphire (SOS), molecular-beam epitaxy (MBE), atomic force microscopy (AFM), lateral force microscopy (LFM), Z-modulation mode.
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Keywords: microelectromechanical systems, nanogyroscope accelerometer.

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